

Search Notes

Application/Control No.

10/724,742

Examiner

Erin M. File

Applicant(s)/Patent under
Reexamination

CHEN, HUNG KUN

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	260	6/27/2006	EMF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	6/27/2006	EMF